



*Industrial Computing Platform Partner*

# **AEC-6420**

**With CFD**

## **Environment Test Report**

**Report NO: 09P020021**

**Issued by:**

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**/**

**07/16/2009**

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**Date**

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**07/16/2009**

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## Test Configuration:

Num	Item	Spec
1.	Control Box:	AEC- 6420
	1. Main Board	AAEON EPIC-9457 Rev. A1.0 (BIOS: 0.A)
	2. CPU	Intel Atom N270 / 1.6GHz
	3. Industrial Memory	DSL 1GB / ELPIDA E5108AGBG-6E-E (DDR2-667)
	5. Industrial CFD	Transcend 4GB
	6. Test Software	Windows XP / Run PassMark Burn In Test 5.1 Pro
	7. Adapter	EDAC EA1050A-120

# Temperature rise test

**Test Date:** 07-15-2009

**Test Product:** AEC-6420

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference EN 61131-2(94), UL508 (94)

**Temperature Measurement:**

40 Channel Thermal Recorder:

YOKOGAWA Inc,

Model: DA100-13-1D

Date of Calibration: 12/08/08

Serial Number: 12A323190

**Test Condition:**

Ambient temperature: 45dC

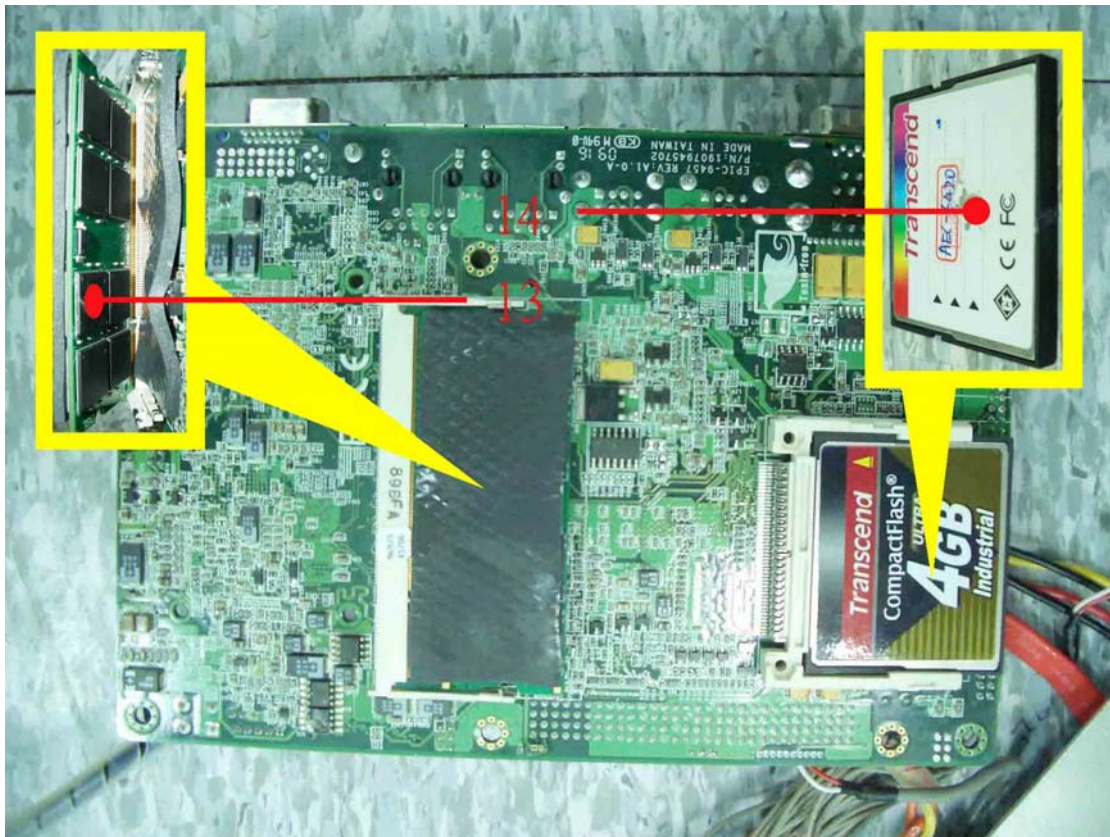
Continuous running till thermal stability (within less than 1°C)

**Test Software:**

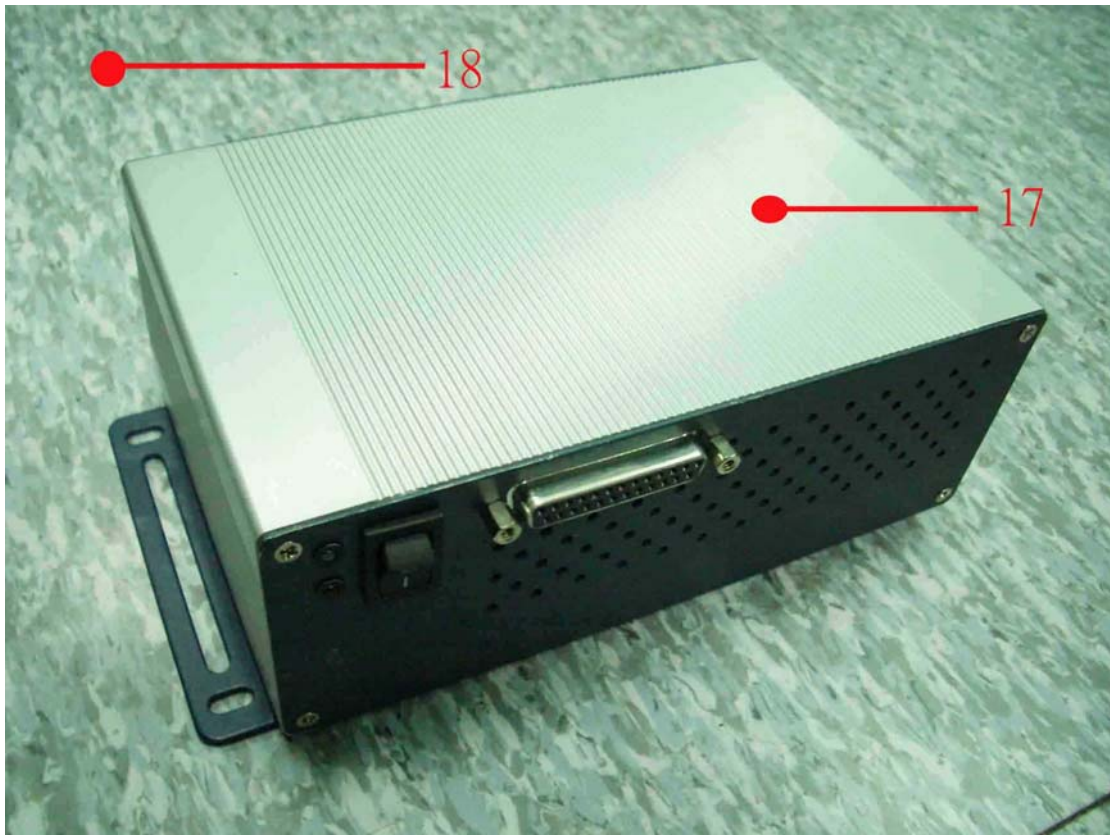
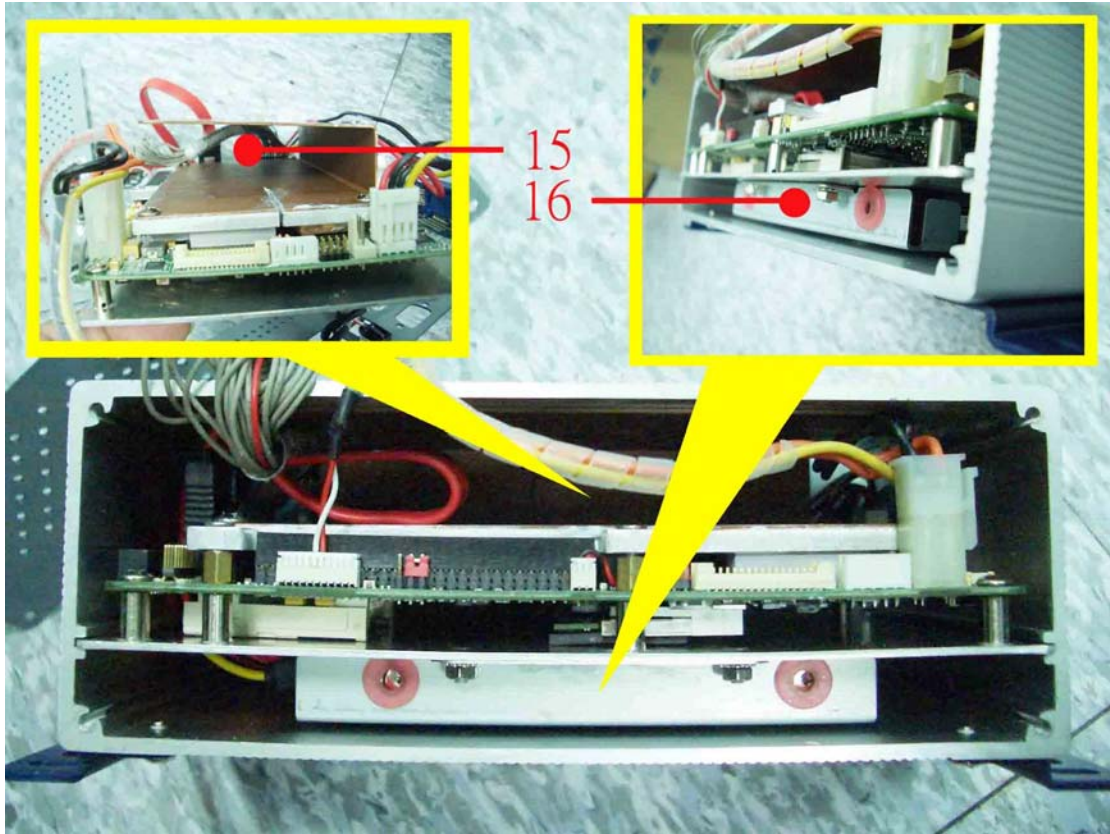
Windows XP / Run PassMark Burn In Test 4.0 Pro

**Terminal Recorder:**

Measuring Thermal Couple Position :



# Temperature rise test



# Temperature rise test

## Thermal profile data:

### AEC-6420

Point	Temp. Stage(°C)	Spec	45	25
<b>EPIC-9457</b>				
01. CPU		90	85.1	65.1
02. U10 - (TF) Intel 945GSE Express Chipset.Intel.QG82945GSE SLB2R		105	101.6	81.6
03. Q5 - (TF) PWR N-Channel.30V.12A.ANPEC.APM4410KC-TRL		125	100.6	80.6
04. U26 - (TF) Super I/O w/4 COMs.ITE.IT8781F/AX-L		100	87.5	67.5
05. U18 - (TF) CLOCK GENERATOR.IDT.9LPRS501PGLF		100	88.6	68.6
06. U29 - (TF) PCI-E GigaBit Ethernet Chipset.Intel.WG82574L SLBA8		100	86.4	66.4
07. U30 - (TF) PCI-E GigaBit Ethernet Chipset.Intel.WG82574L SLBA8		100	88.5	68.5
08. U4 - (TF) 6 Channel AC'97 Audio Codec.REALTEK.ALC655-LF		100	88.1	68.1
09. UU7 - (TF) ICH7M.Intel.NH82801GBM SL8YB		99	90.1	70.1
10. Q33 - (TF) PWR .N-Channel.30V.12A.ANPEC.APM4420KC-TRL		125	104.9	84.9
11. Q32 - (TF) PWR .N-Channel.30V.12A.ANPEC.APM4420KC-TRL		125	102.2	82.2
12. U40 - (TF) REG. Linear Regulator.Diodes.AP1084DL-13		150	88.6	68.6
13. Industrial Memory		95	88.5	68.5
14. Industrial CFD		85	78.9	58.9
15. Control Box Internal Air Temperature - 1		N/A	71.5	51.5
16. Control Box Internal Air Temperature - 2		N/A	70.1	50.1
17. Control Box External Surface		N/A	67.5	47.5
18. Chamber Air Temperature		N/A	44.9	24.9
<b>Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.</b>				

## Sample Configuration & Quantity Under Test:

Quantity: 1 (AEC-6420)

## Test Result:

No problem was found during the temperature rise operation test.

# Temperature cycle test

**Test Date:** 07-03~06-2009

**Test Product:** AEC-6420

**Test Site:** AAEON QA Internal Lab.

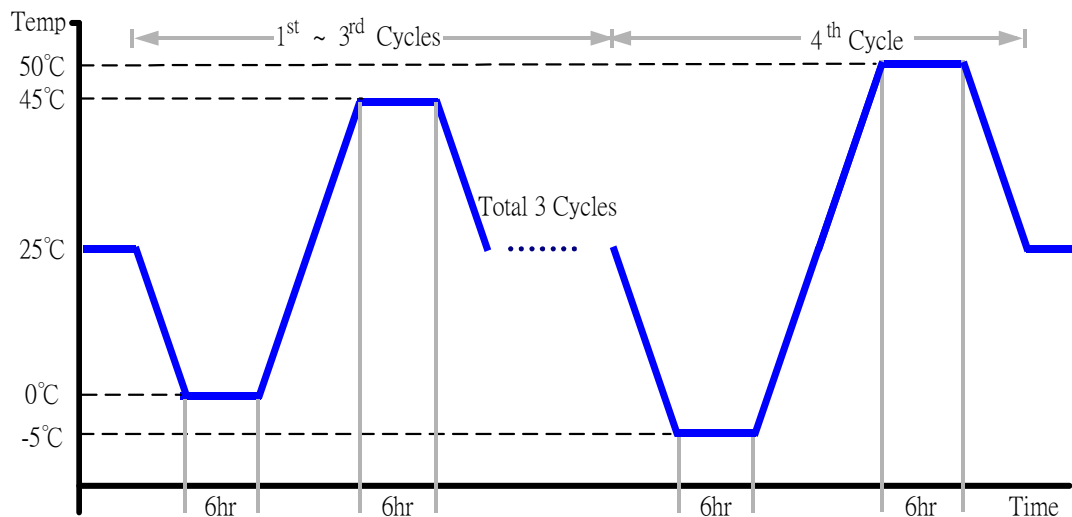
**Test Standard:** Reference IEC68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4L+-100  
Date of Calibration: 05/07/08  
Serial Number: 1241

**Test Condition:**

1. Test Low Temperature: 0°C (1~3 cycles)  
-5°C (4<sup>th</sup> cycle)
2. Test High Temperature: 45°C (1~3 cycles)  
50°C (4<sup>th</sup> cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AEC-6420)

**Test Result:**

No problem was found during the temperature operation cycle test.

**Test Date:** 07-06~08-2009

**Test Product:** AEC-6420

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-2 Testing procedures  
Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.

Model: THS-D4L+-100

Date of Calibration: 05/07/08

Serial Number: 1241

**Testing Item:**

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AEC-6420)

**Test Result:**

No problem was found after the high temperature storage test.

**Test Date:** 07-08~10-2009

**Test Product:** AEC-6420

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-1 Testing procedures  
Test Ab: Cold Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.

Model: THS-D4L+-100

Date of Calibration: 05/07/08

Serial Number: 1241

**Testing Item:**

1. Test Temperature: -10°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (AEC-6420)

**Test Result:**

No problem was found after the low temperature storage test.



# Humidity test

**Test Date:** 07-10~12-2009

**Test Product:** AEC-6420

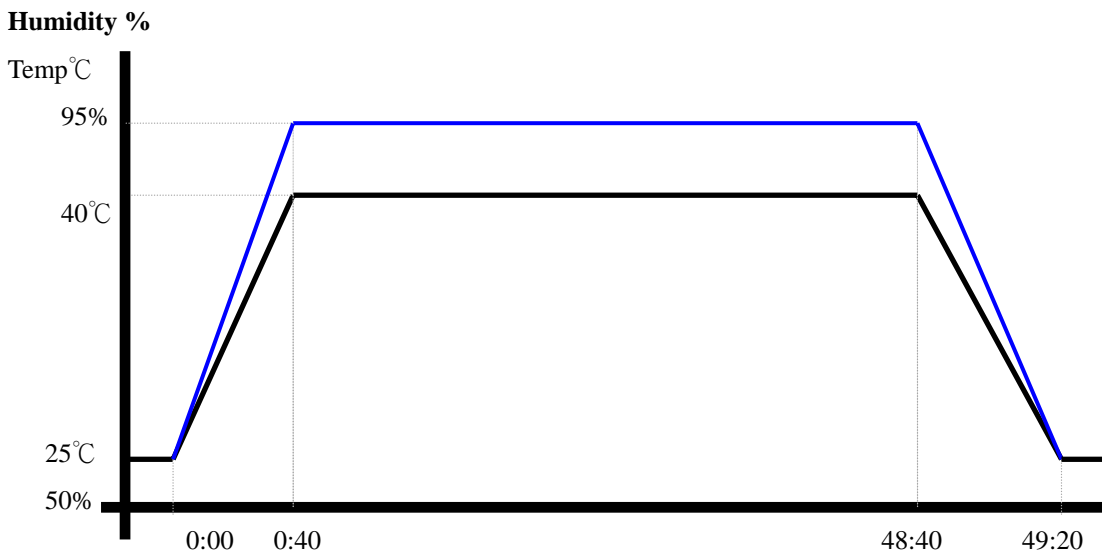
**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-3 Testing procedures  
Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4L+-100  
Date of Calibration: 05/07/08  
Serial Number: 1241

**Testing Item:**

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (AEC-6420)

**Test Result:**  
No problem was found after the humidity storage test.

# Cold start and hot start test

**Test Date:** 07-13~14-2009

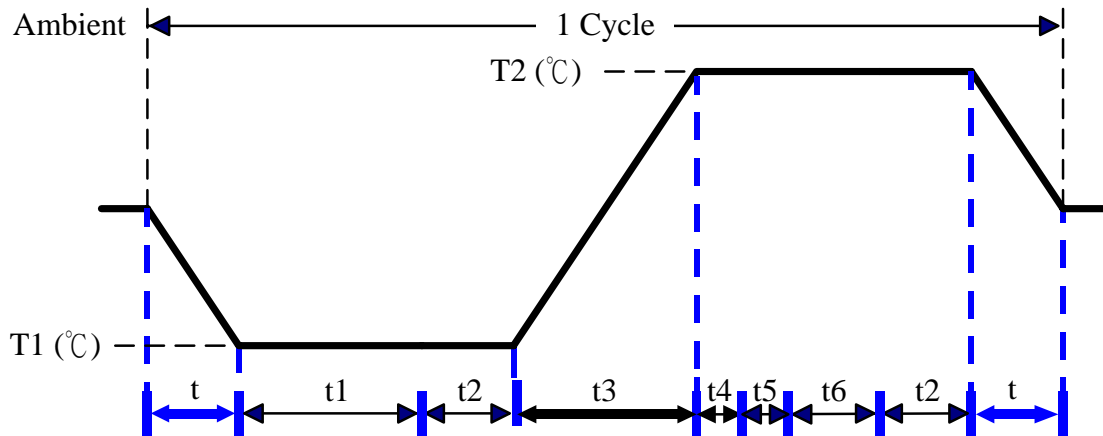
**Test Product:** AEC-6420

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4L+-100  
Date of Calibration: 05/07/08  
Serial Number: 1241

**Test Condition:**



Parameters	Description
T1	-5°C
T2	50°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1 hrs
t, t3	2°C/min
n (Cycle)	1

t = temperature slope  
t, t1, t6: Power Off  
t2: Power on/off test 10 times (on 2 min / off 5min)  
t3, t4: Run PassMark Burn In Test  
t5: Win XP Software restart test 3 times  
Test Software: Windows XP

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.